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PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10067819	FILING DATE 02/08/2002	CLASS 324	SUBCLASS 714	GAU 2133 2858	EXAMINER <i>Beardy</i>
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*K3D* *KERVERUS*

\*\*CONTINUING DATA VERIFIED: *None*  
*in 6/4/2004*

\*\* FOREIGN APPLICATIONS VERIFIED: *YES 6/4/2004*  
JAPAN 2001-136938 05/08/2001  
*in*

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO
35 USC 119 conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	60188-150
Verified and Acknowledged Examiners's Initials <i>in</i>		
TITLE : Integrated circuit and testing method for integrated circuit		
U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)		

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
Assistant Examiner		DRAWING	
ISSUE FEE		Sheets Drwg.	Figs. Drwg.
Amount Due	Date Paid	Print Fig.	
Primary Examiner		Application Examiner	
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	
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